



Advanced Imaging S.L.

Towards Gfps CMOS image sensors

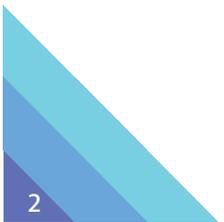
Renato Turchetta

renato.turchetta@imasenic.com

Barcelona, Spain

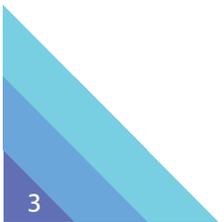
Outline

- **Introduction**
- **High speed CMOS**
- **Towards Gfps**



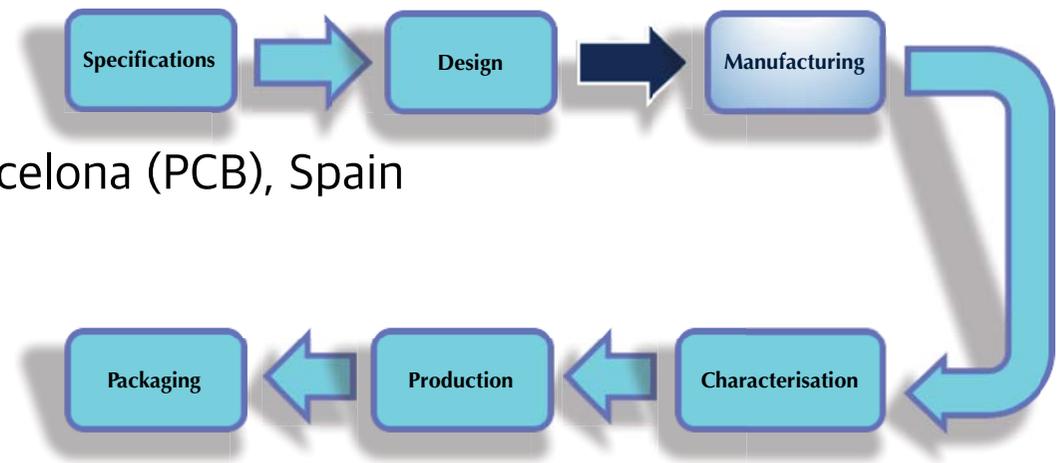
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IMASENIC Advanced Imaging S.L.

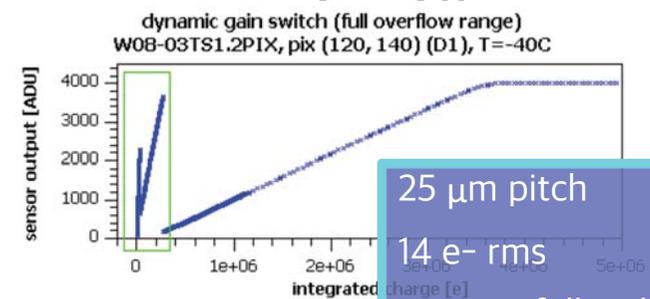
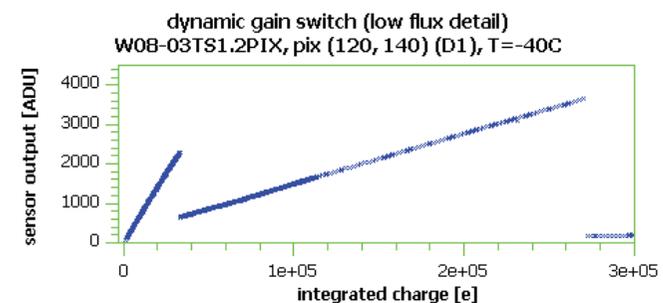
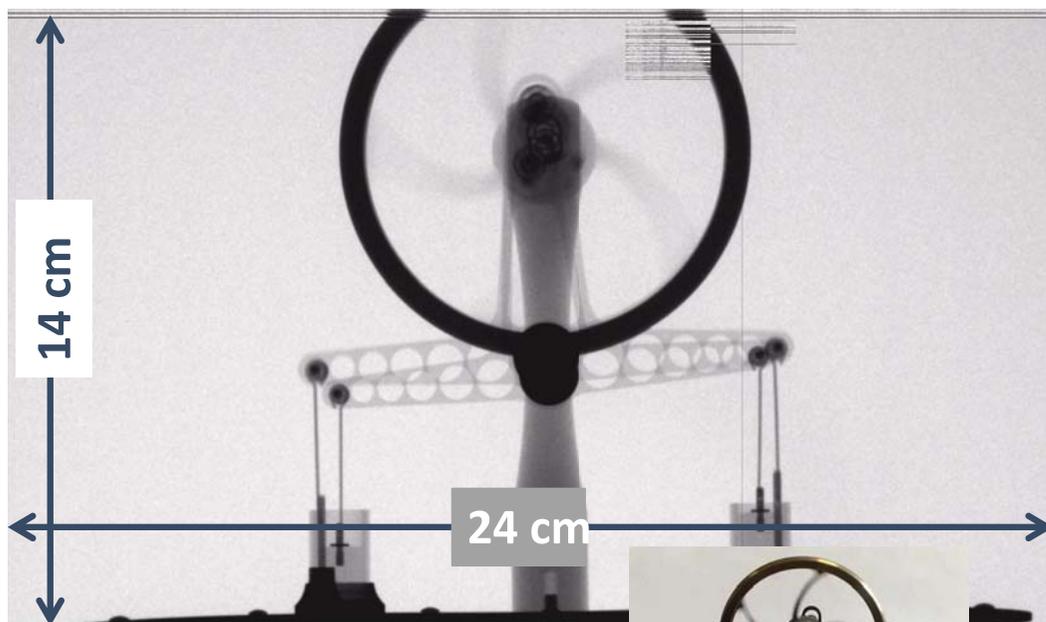
- CMOS Image Sensors design house
- Developing CIS from specifications to production
- Over 40 years of cumulated experience in developing advanced CMOS Image Sensors and mixed-mode ASIC products
- Located at the Parc Científic de Barcelona (PCB), Spain
- www.imasenic.com



Track record. 1

- 3-side buttable, wafer-scale

- High dynamic range

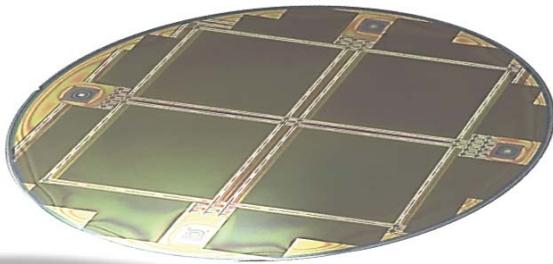


25 μm pitch
14 e^- rms
7.5M e^- full well

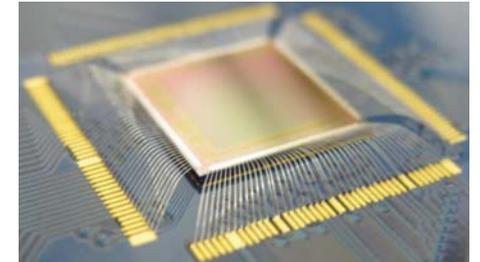


Track record. 2

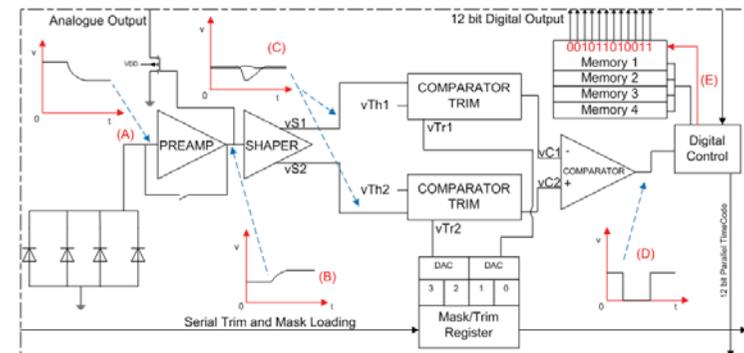
- 16Mpixel rad-hard for TEM



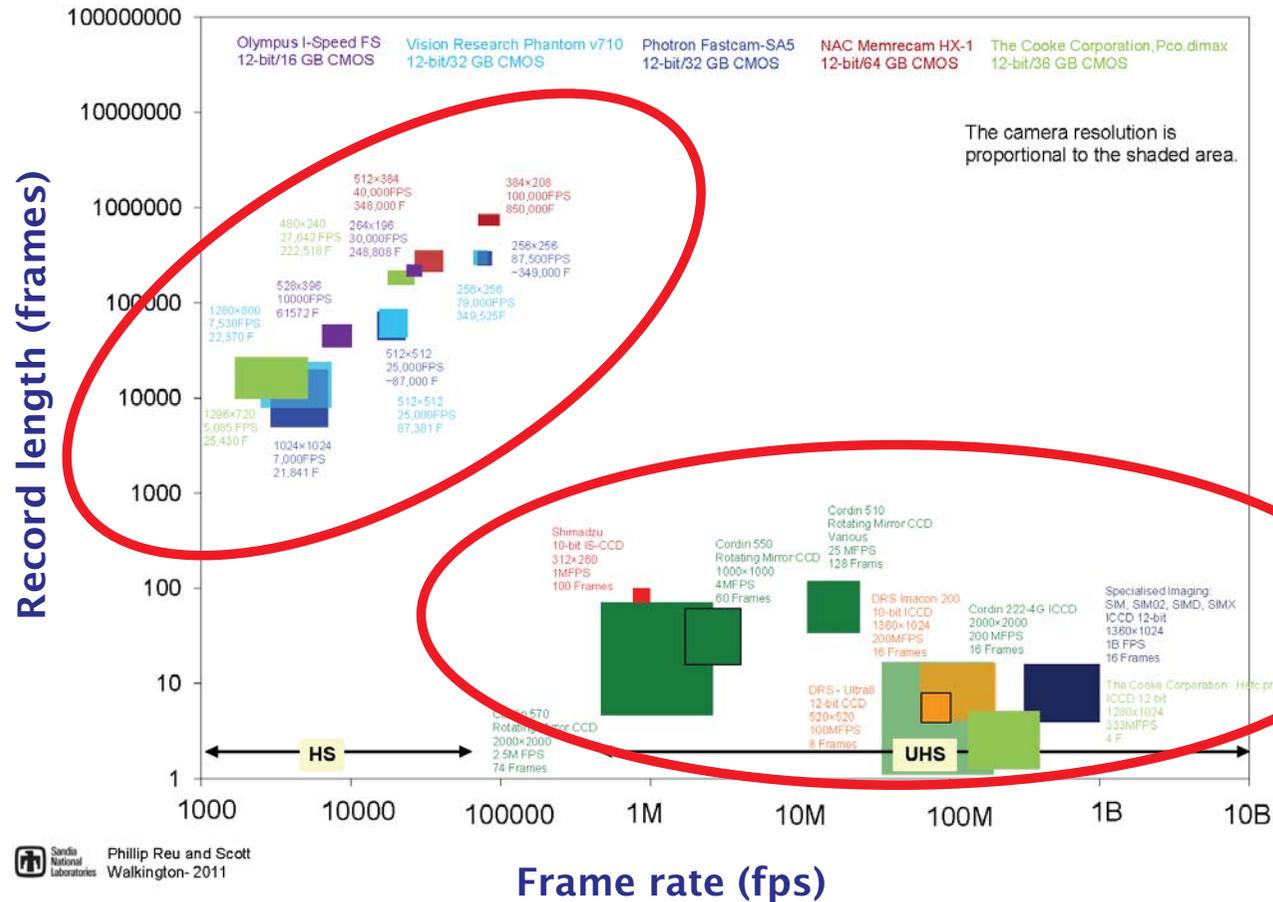
- Single Photon Avalanche Detectors



... and complex (smart) pixels



High/Ultra-high speed imagers



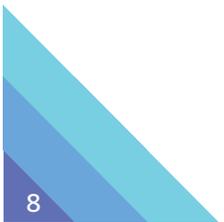
The camera resolution is proportional to the shaded area.

This is a 1 Mpixel sensor



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- Towards Gfps



Frame rate deconstructed

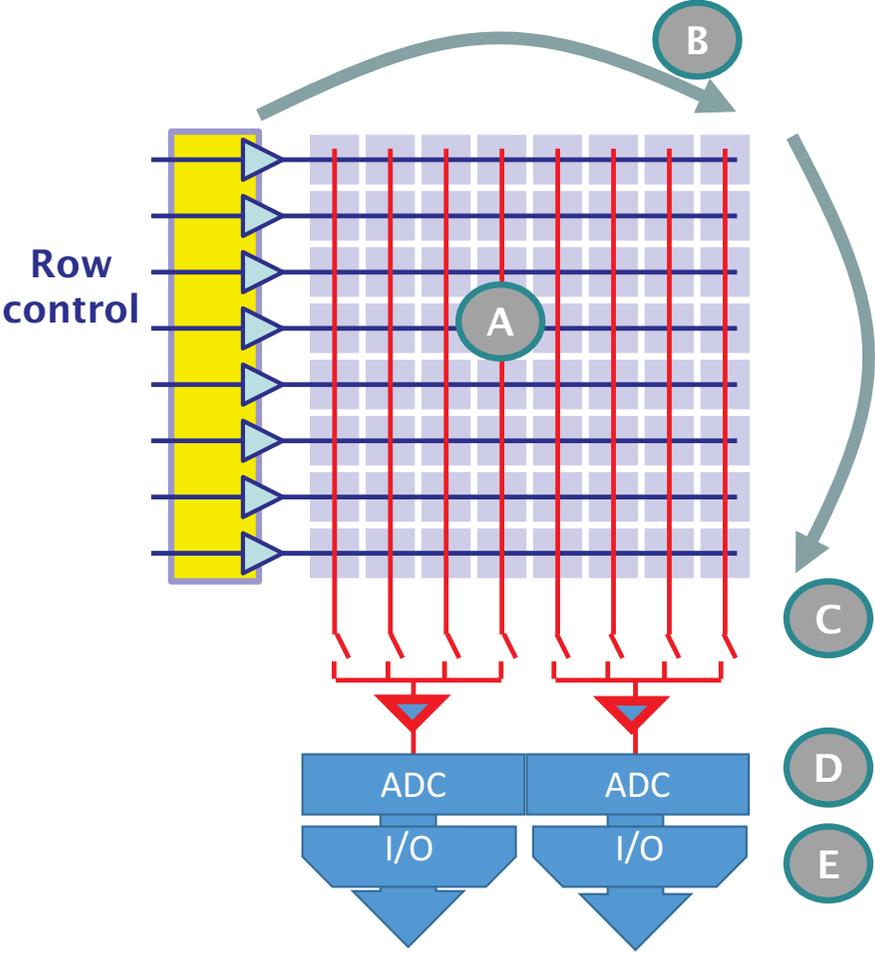
A) Charge collection

B) Time to select a row

C) Time to settle the data at
the periphery

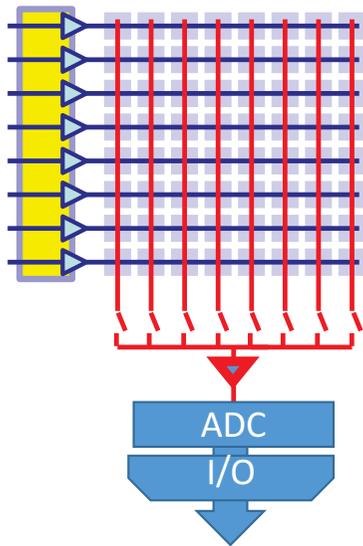
D) Analogue-to-Digital
Conversion

E) I/O

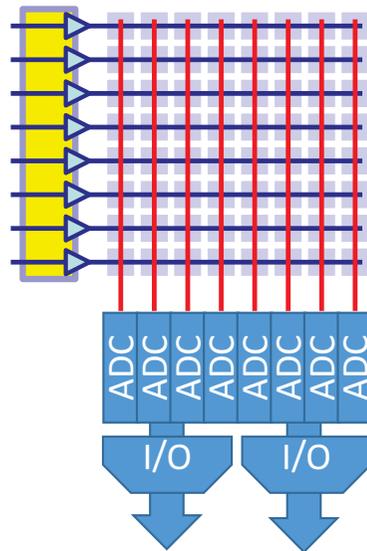


ADC options

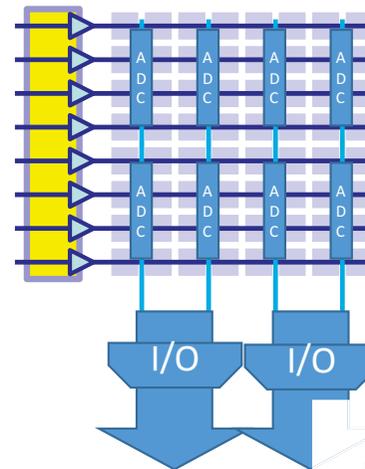
Global (chip)



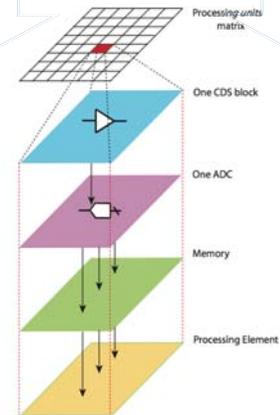
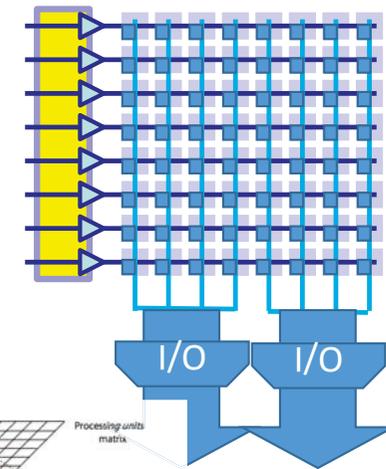
Column-parallel



Block



Per-pixel



ADC architectures

Figure of Merit =
 Noise *
 (Pitch)²*
 Power/
 (2^{Nbits}*F_s)

F_s = sampling frequency

[μJ μV_{rms} μm²]

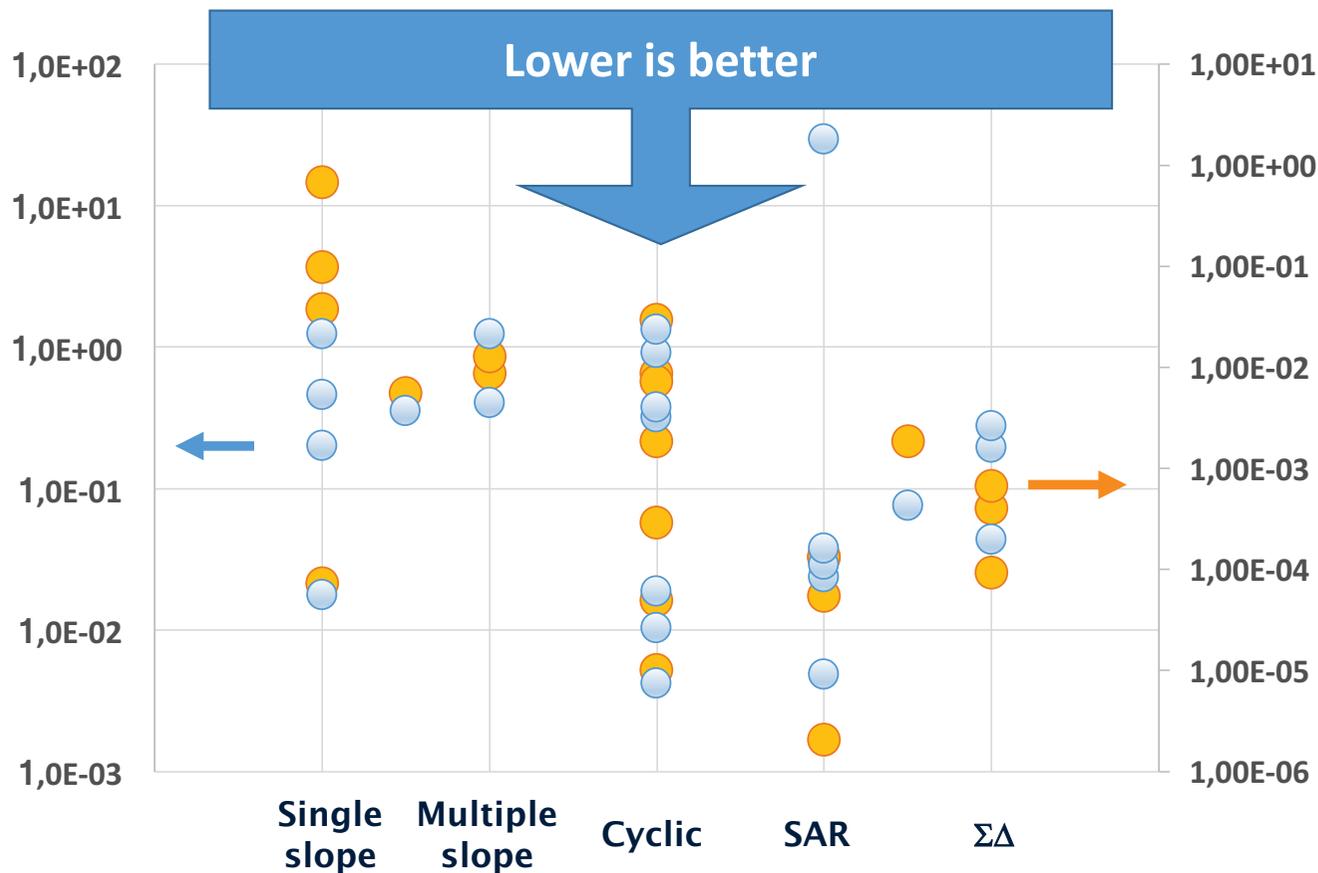


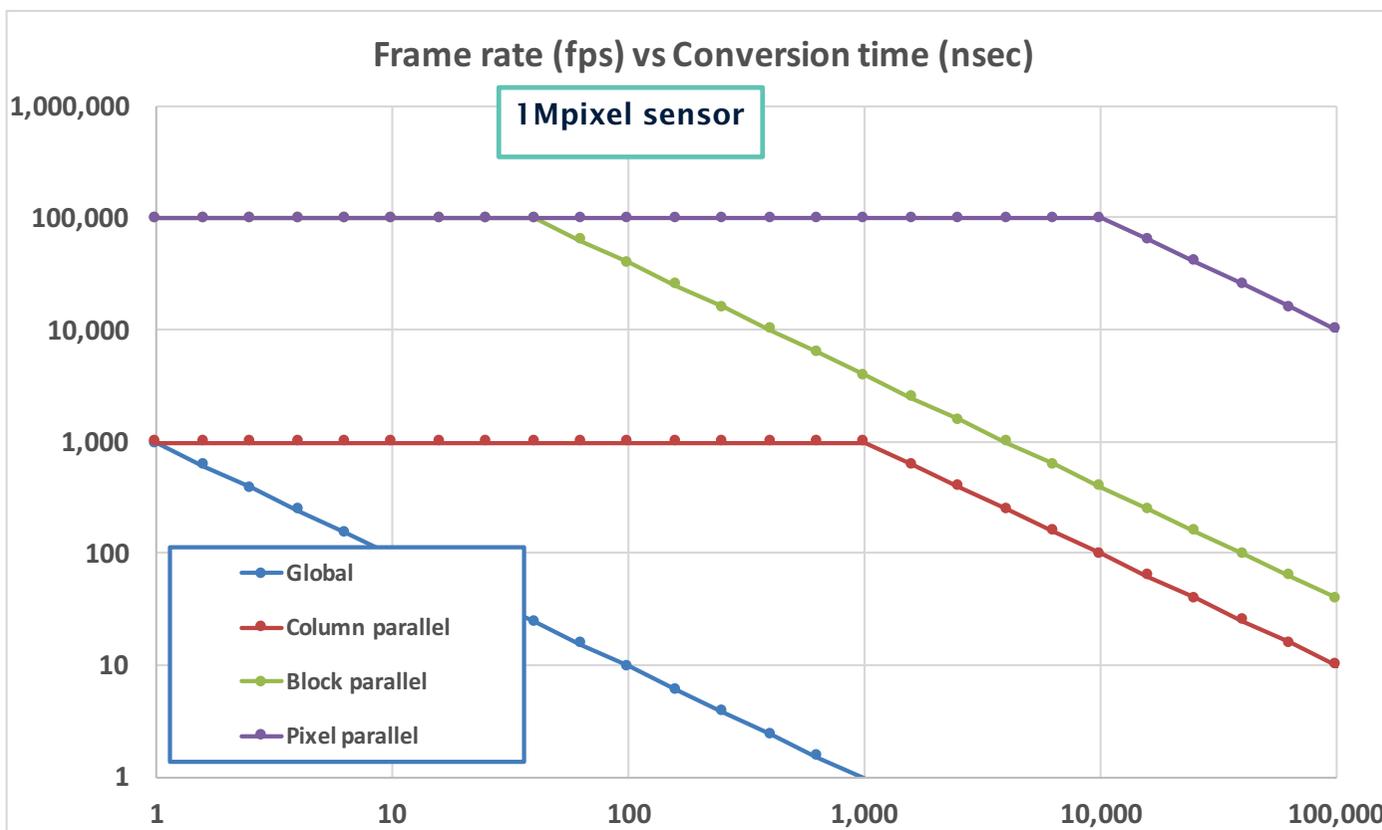
Figure of Merit =
 Noise *
 Area*
 Power/
 (2^{Nbits}*F_s)

F_s = sampling frequency

[μJ μV_{rms} μm²]



Frame rate



16x16 blocks

1 ADC per column

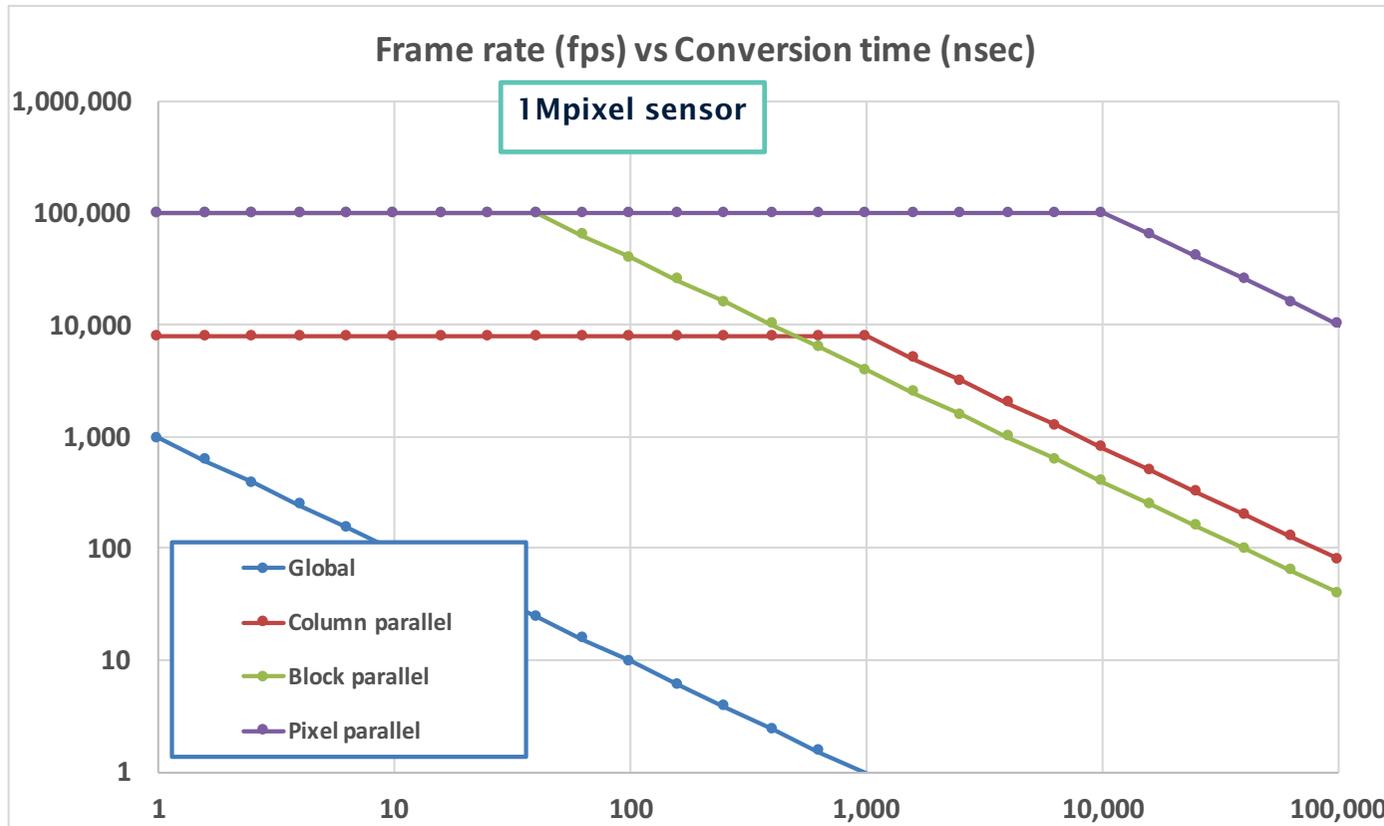
2 Gbit/sec IO

10 bit accuracy

1µsec blanking time (and proportional for block r/o)

512 IOs (10 for Global ADC)

Frame rate



16x16 blocks

8 ADCs per column

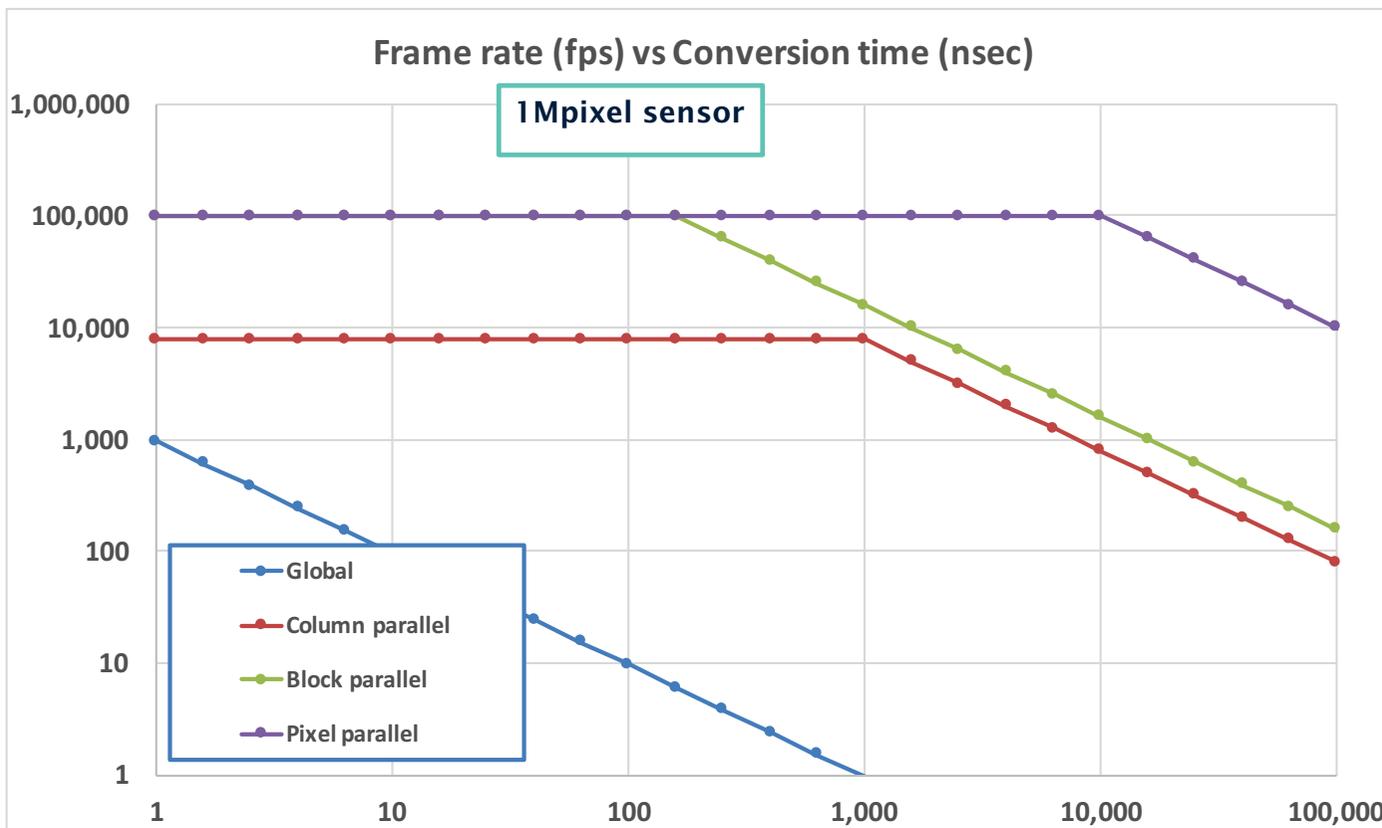
2 Gbit/sec IO

10 bit accuracy

1 μ sec blanking time (and proportional for block r/o)

512 IOs (10 for Global ADC)

Frame rate



8x8 blocks

8 ADCs per column

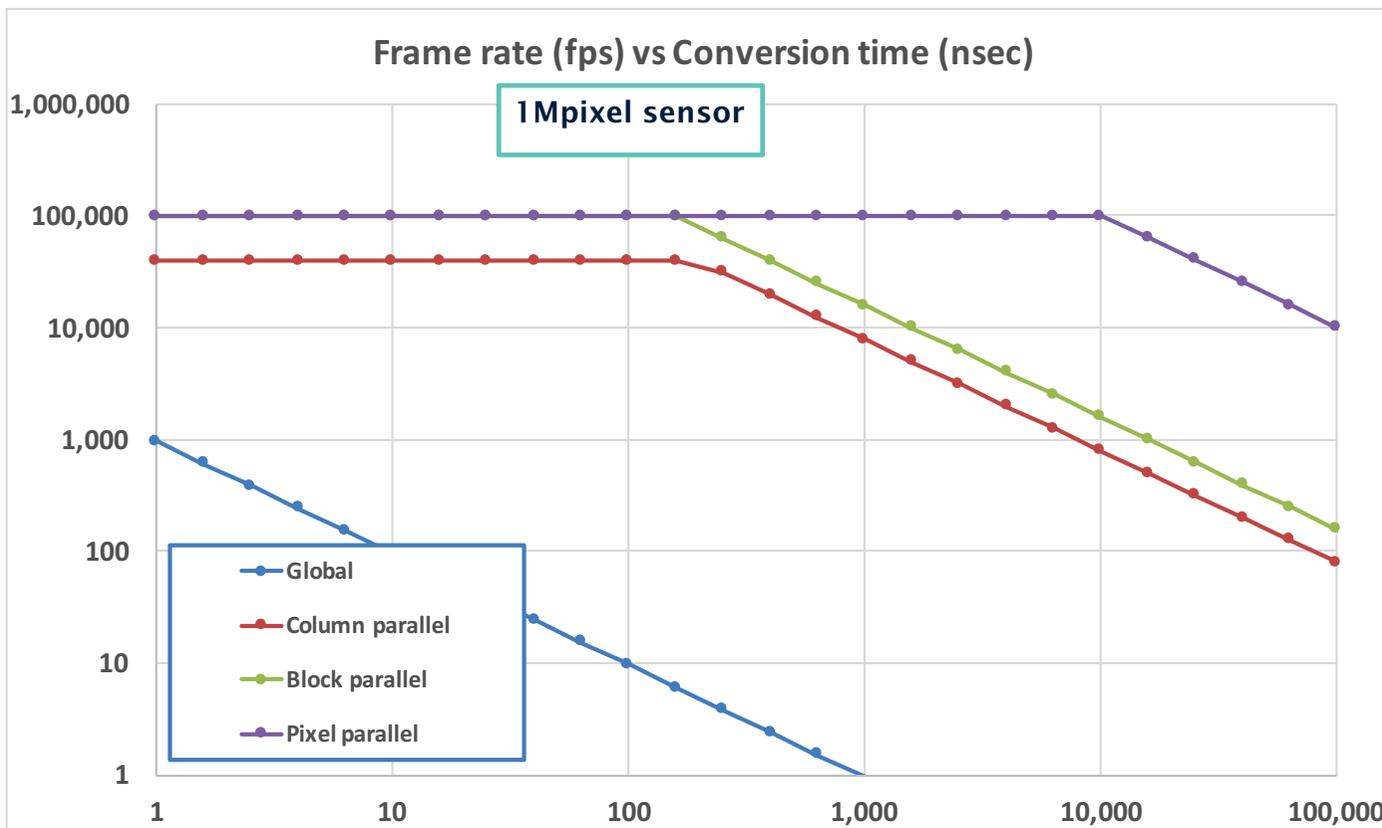
2 Gbit/sec IO

10 bit accuracy

1µsec blanking time (and proportional for block r/o)

512 IOs (10 for Global ADC)

Frame rate



8x8 blocks

8 ADCs per column

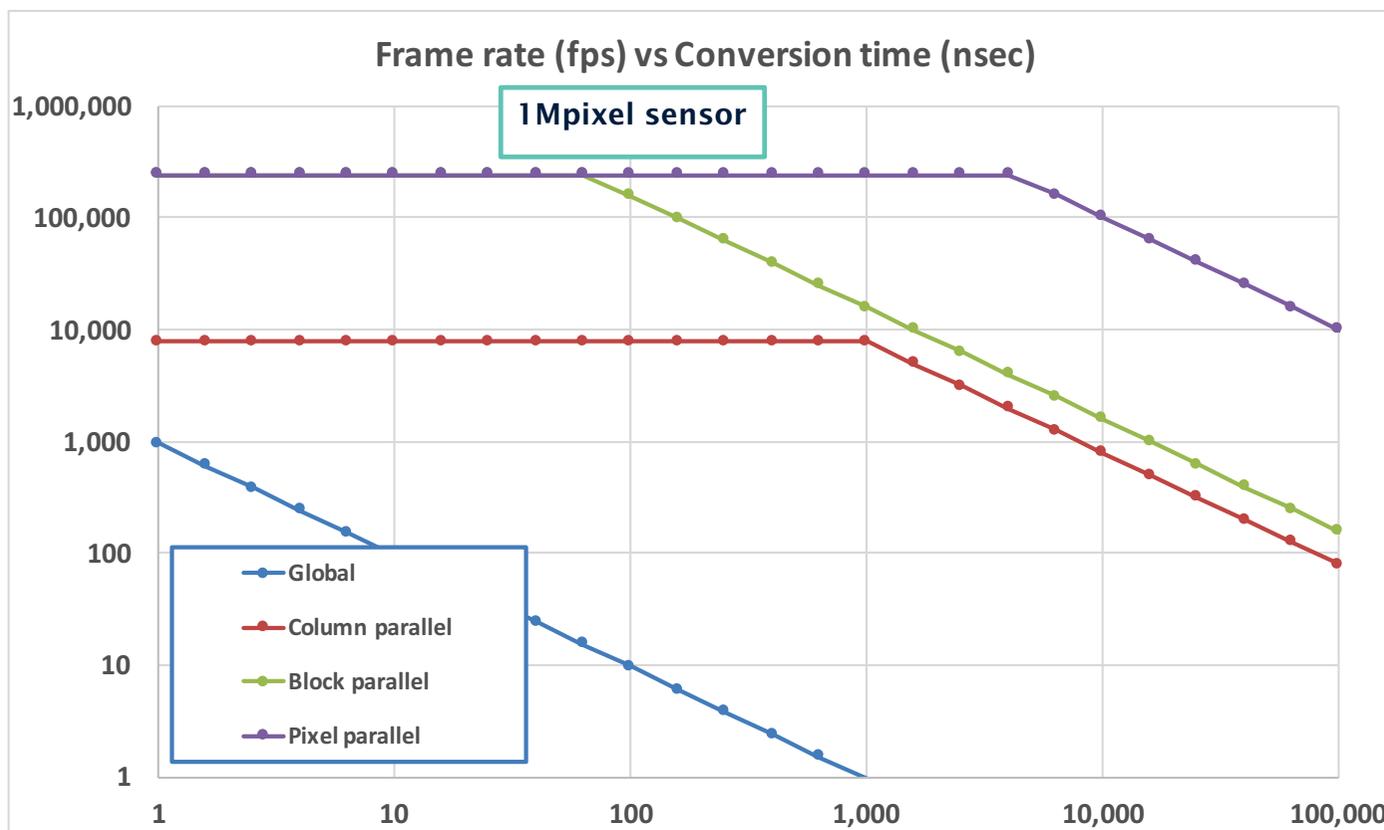
2 Gbit/sec IO

10 bit accuracy

0.2µsec blanking time (proportional for block r/o)

512 IOs (10 for Global ADC)

Frame rate



8x8 blocks

8 ADCs per column

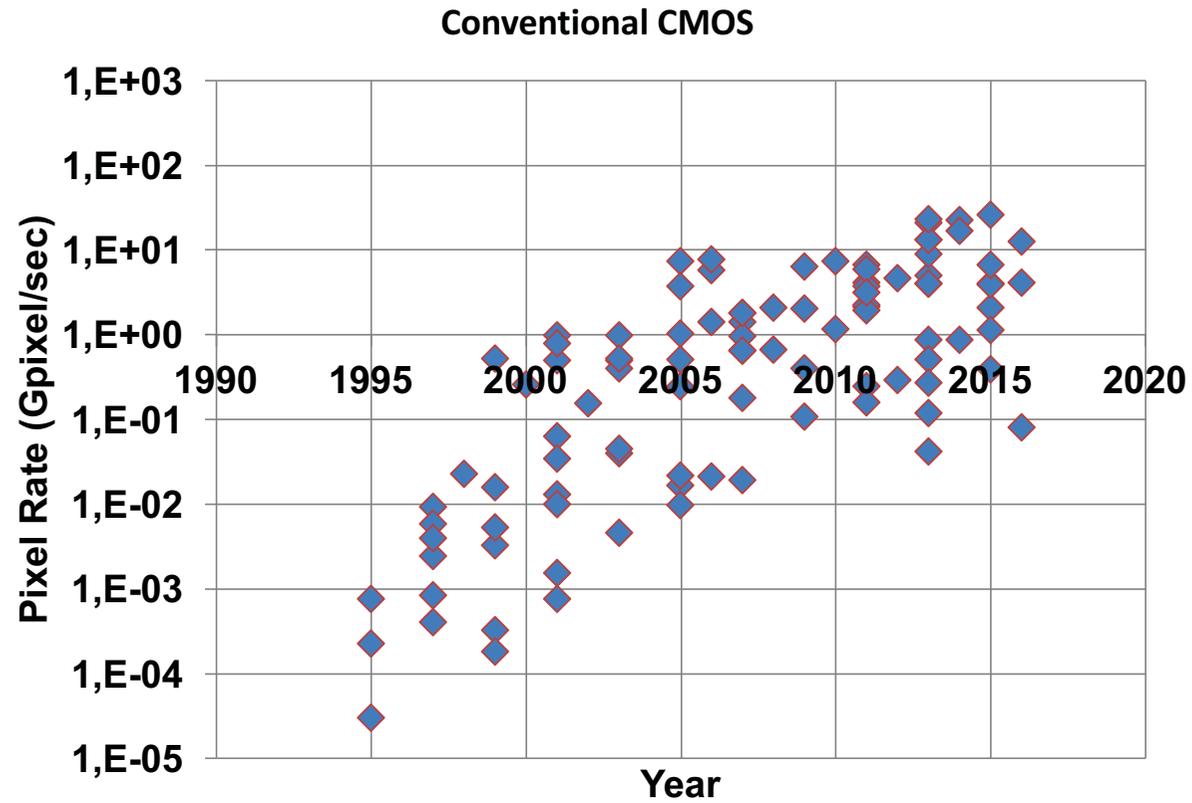
5 Gbit/sec IO

10 bit accuracy

1µsec blanking time (and proportional for block r/o)

512 IOs (10 for Global ADC)

High-speed summary.



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- **Towards Gfps**

Ramo-Shockley's theorem

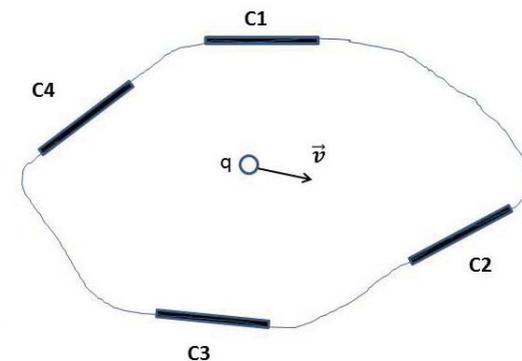
Current $i(t)$ on one electrode due to a charge q moving with speed $v(t)$ at point

$$i_k(t) = q \vec{v} \cdot \vec{E}_w$$

$E_w(x)$ is the electric field obtained by setting the selected electrode at unit potential, all other electrodes at zero potential. (Shockley 1938, Ramo 1939)

$E_w(x)$ calculated after removing all space charge .

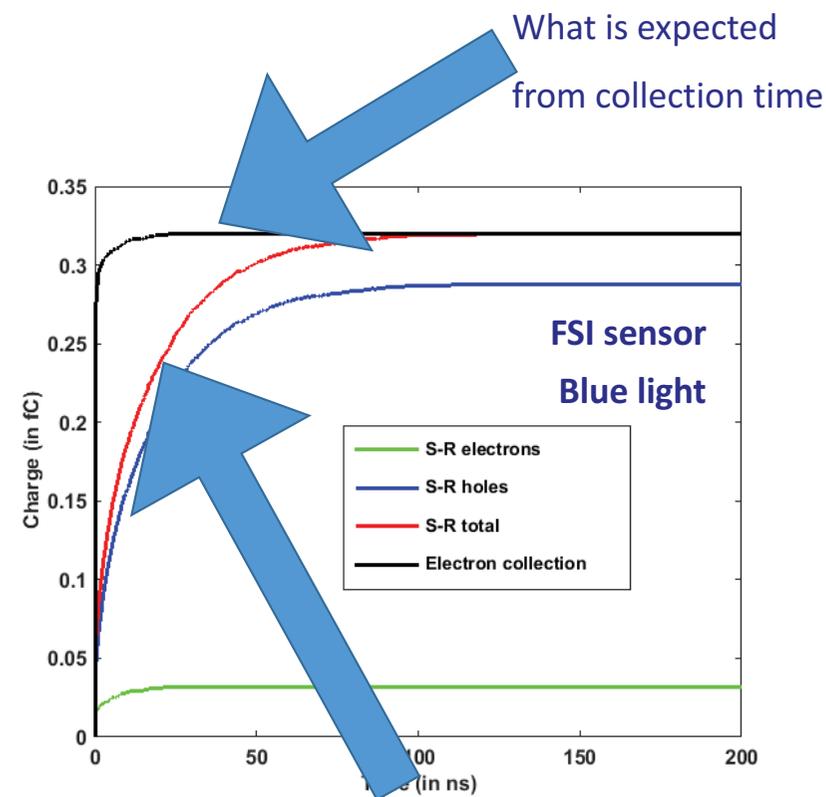
(Cavalleri et al. 1971)



The current signal is induced by the movement of charge

Consequences

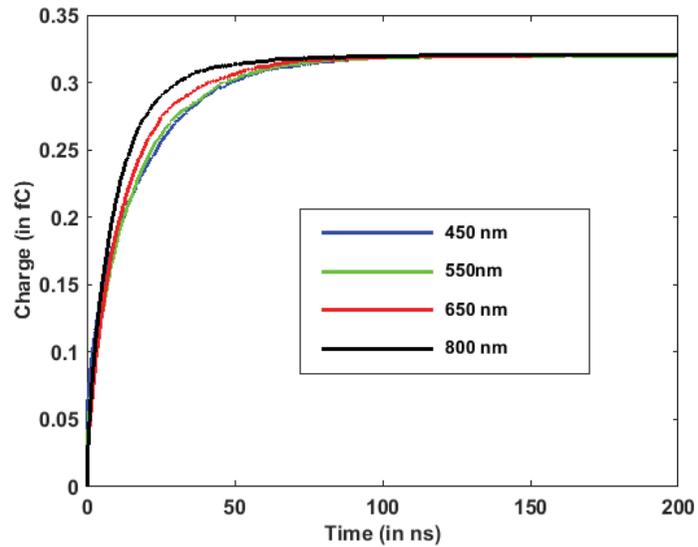
- The current signal is induced by the movement of charge
- In semiconductor there are two types of carriers, electrons and holes, hence two current components
- The two components are summed to give the total current
- The integral of the total (sum) current is equal to the collected charge



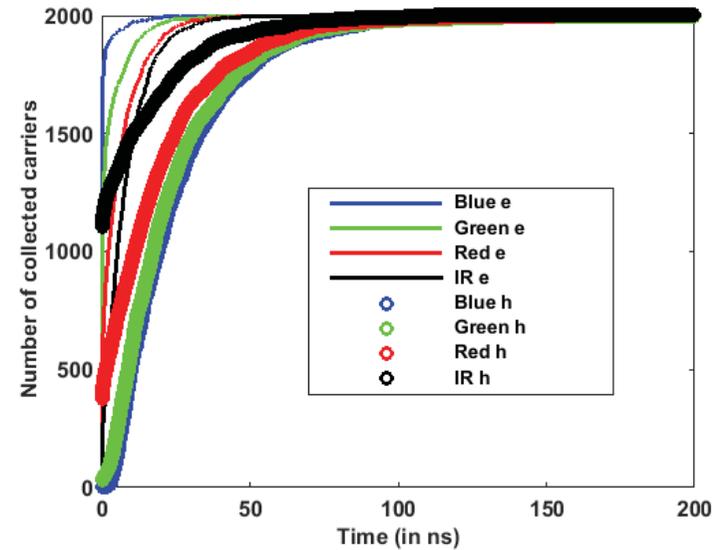
What is predicted by Shockley-Ramo

Temporal colour cross-talk

Ramo-Shockley



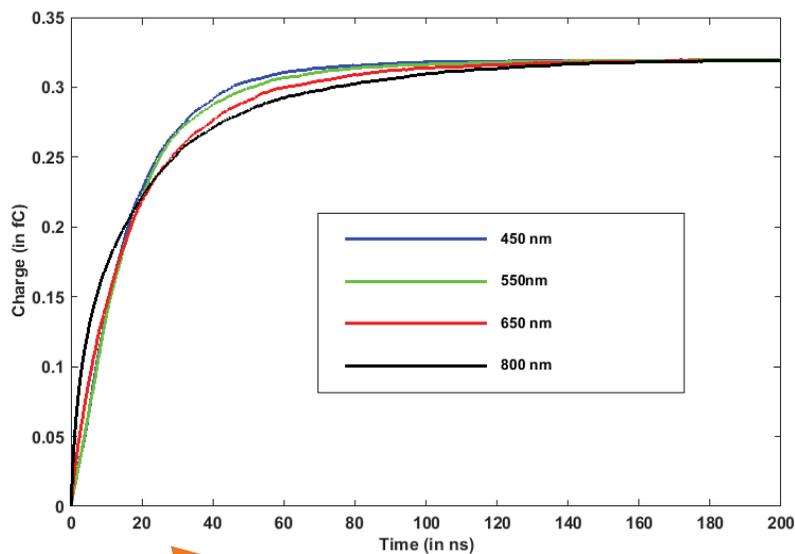
Carrier collection



Thin epi. Low resistivity.

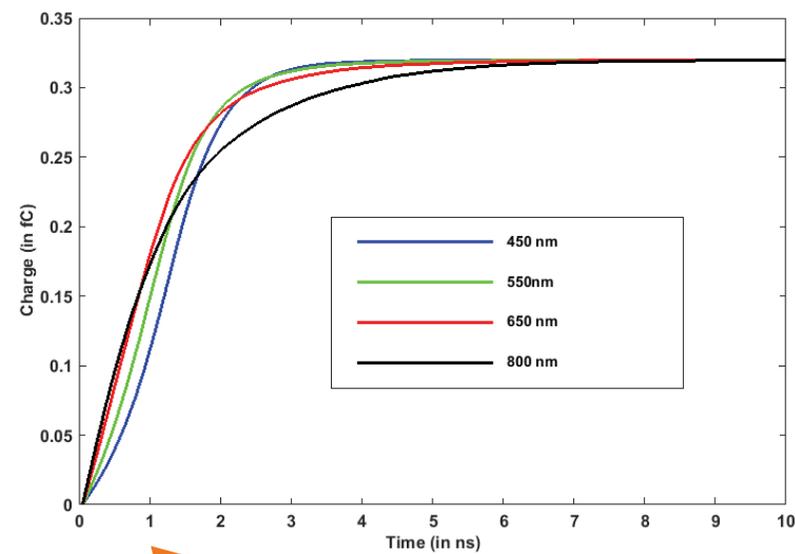
Overbias on a 12μm thick epi

$V_{bias} = 1.5V$



20 ns

$V_{bias} = 5V$

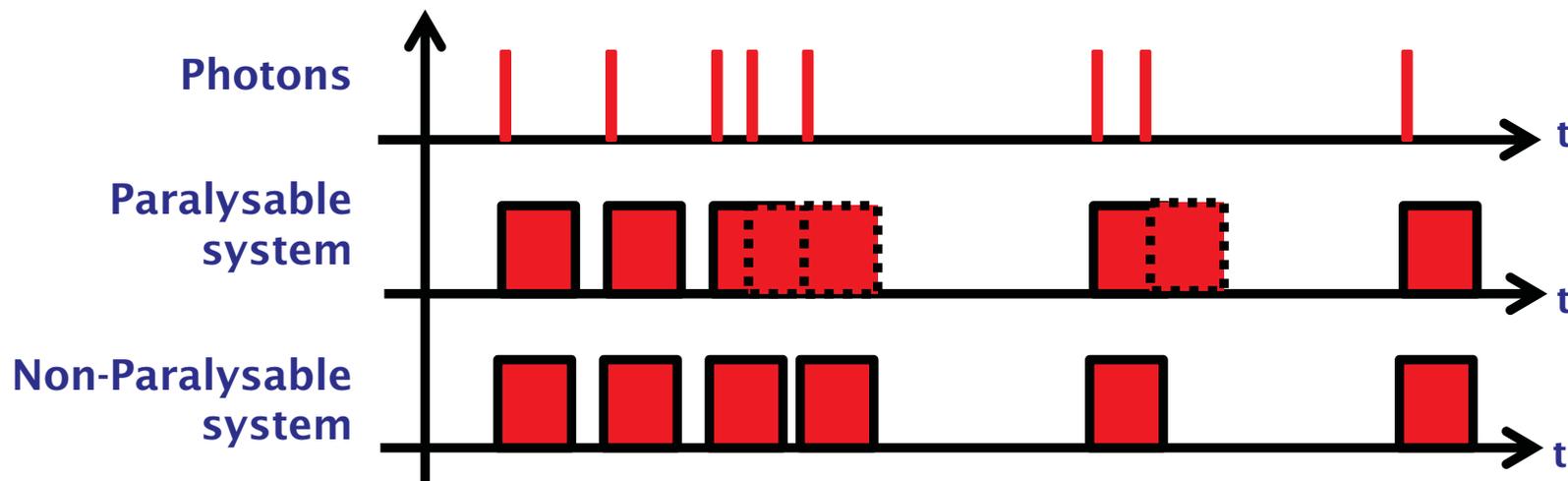


1 ns

Sub-ns collection time > Gfps frame rate

What about photon counting ?

Deadtime in counting systems. Basic models: paralyzable and non-paralyzable



Counting curves

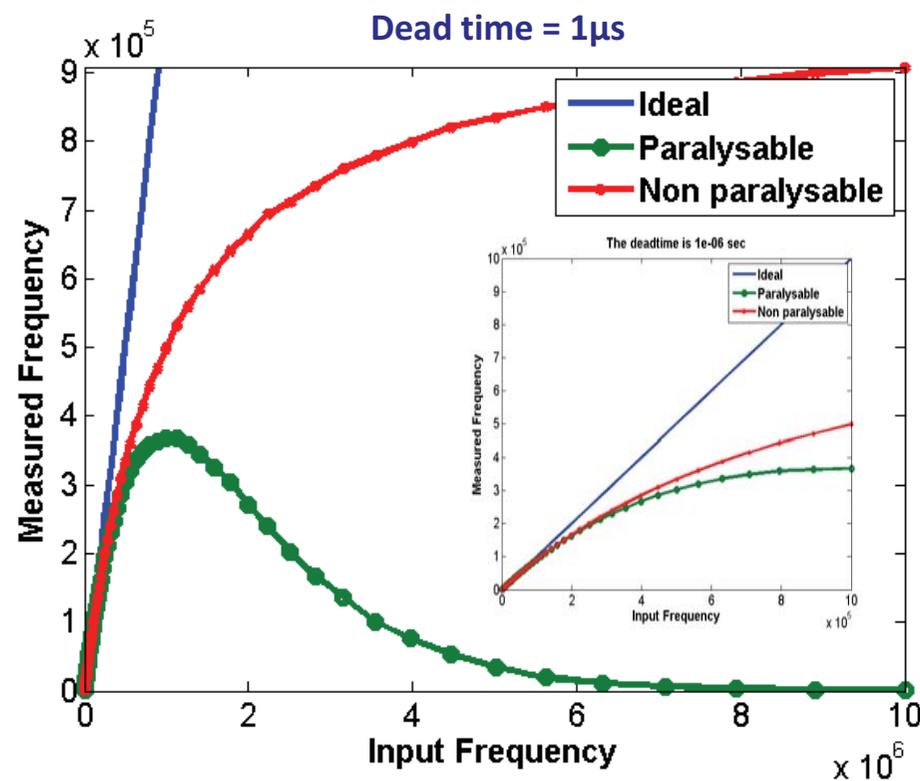
Maximum count rate set by
dead time

Linear counting rate $\sim 1 / (10 * \text{deadtime})$

Frame rate $\uparrow \downarrow$

Maximum count $\downarrow \downarrow$

Bit depth



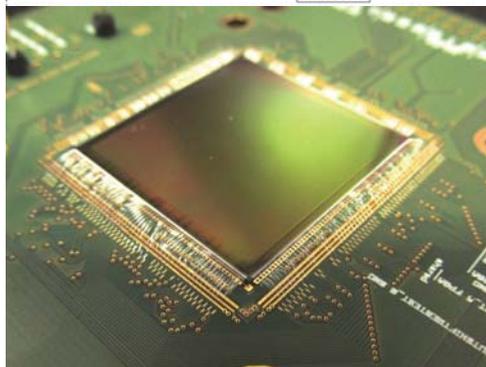
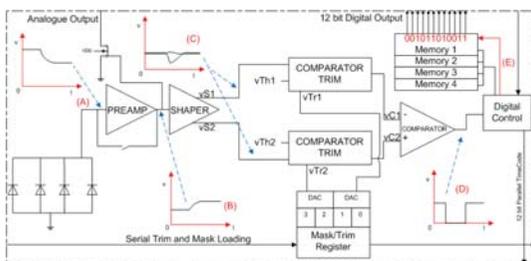
Practical implementation

Towards Gfps

- A) Time stamping (photon counting)
- B) Time Pixel Multiplexing
- C) Burst (framing) image sensors

Time stamping

In-pixel signal conditioning



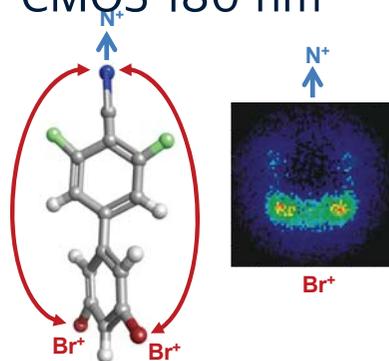
PIImMS

388x388

Standard diodes

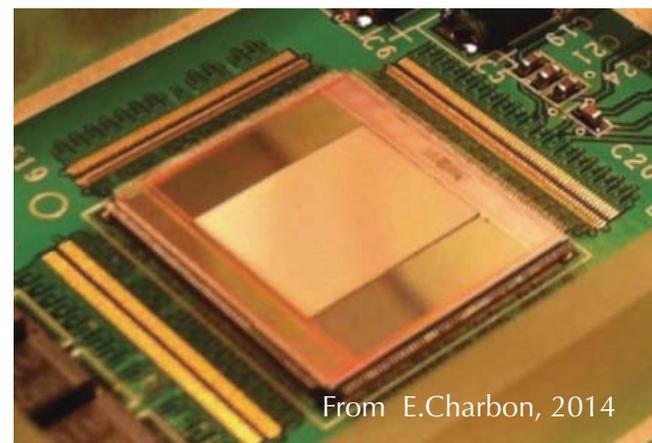
Timing resolution (12.5 ns)

CMOS 180 nm



Single-photon Avalanche detectors (SPAD)

Megaframe



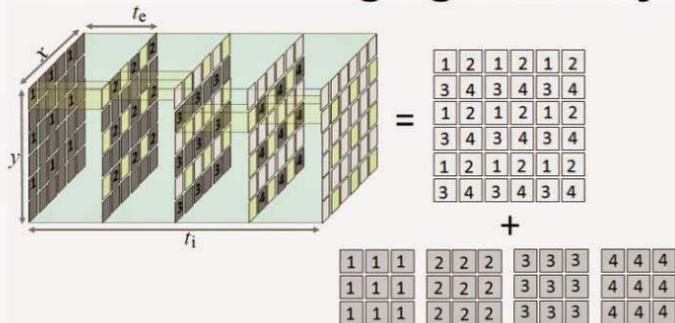
160x128 SPAD

Timing resolution (119 ps FWHM)

CMOS 130 nm

Time Pixel Multiplexing

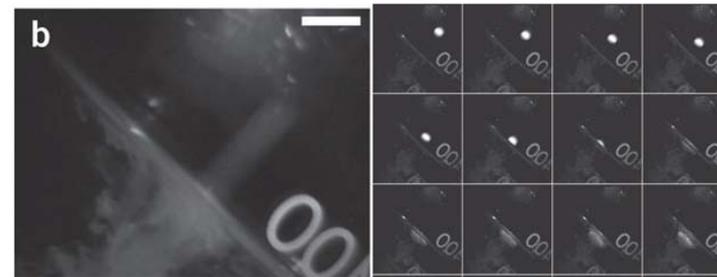
TPM – a new imaging modality



Gives a high resolution image & a high speed image sequence –

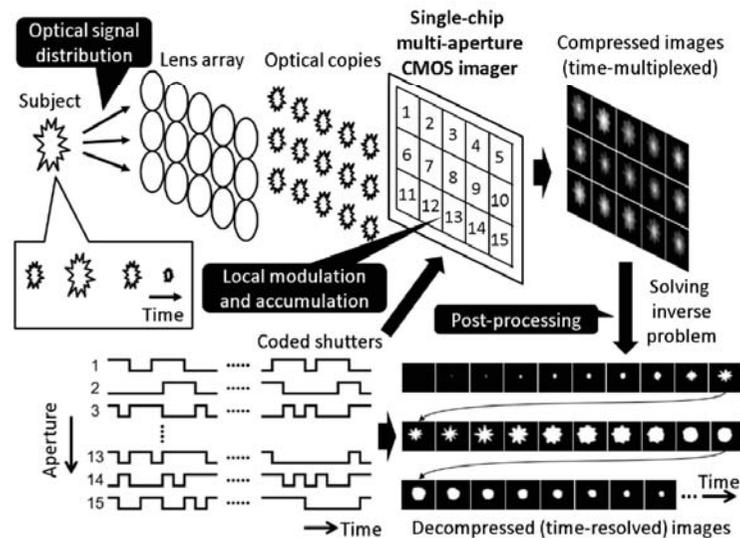
- *in a single picture*
- *with no added read noise*

Courtesy of G. Bub, Oxford University, 2016



High resolution still picture acquired to a lower resolution, high-speed video

Conventional camera used together with Digital Micromirror Devices (DMD)



Multiple sensors on same substrate

F. Mochizuki et al., ISSCC 2015

Figure 6.4.1: Overall flow of image acquisition and reproduction with a multi-aperture single-chip CMOS imager.

Burst (framing) sensors

On-chip storage

A) Voltage storage

Sample voltage on capacitor

B) Charge storage

Charge is stored and transferred to readout node

Voltage mode

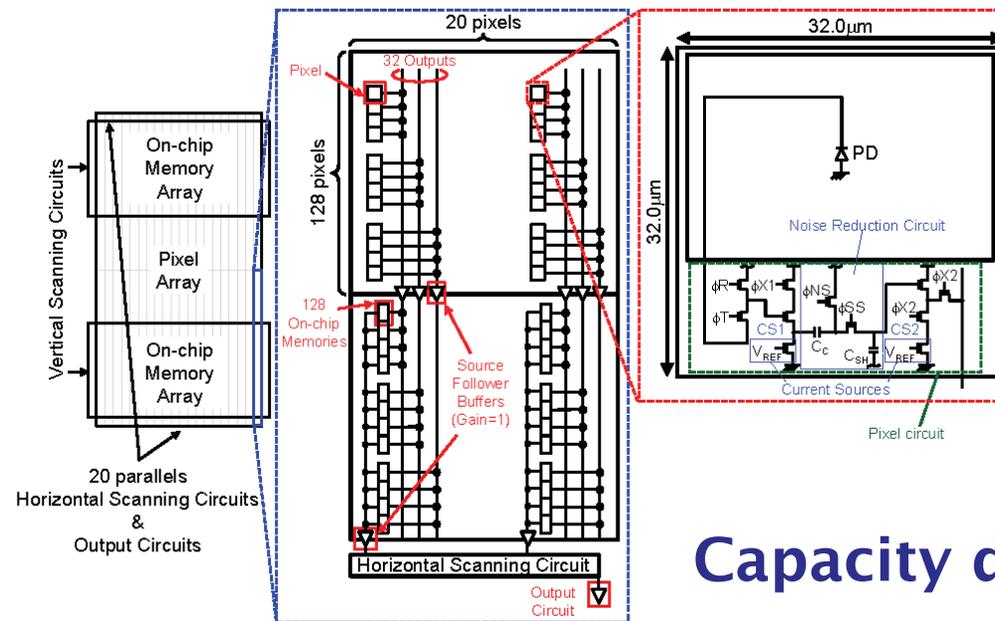
On-chip storage

'Brute force'

global shutter

Data stored in

periphery

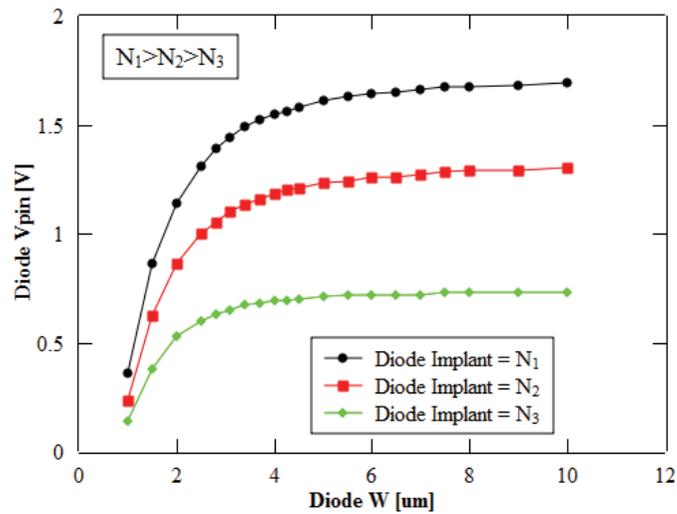


Tochigi,
2013

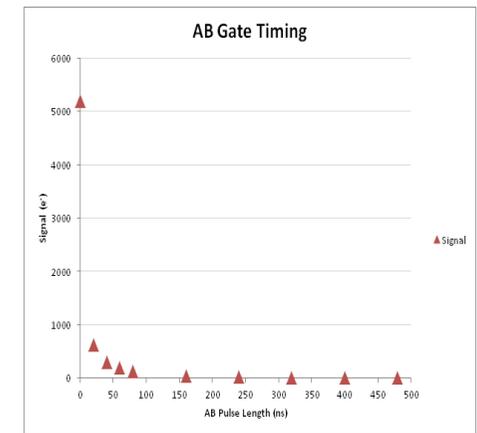
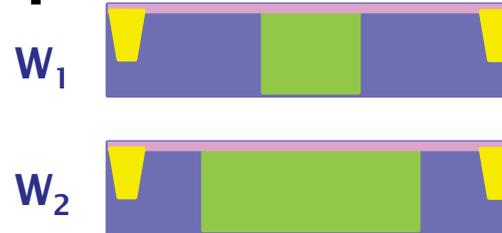
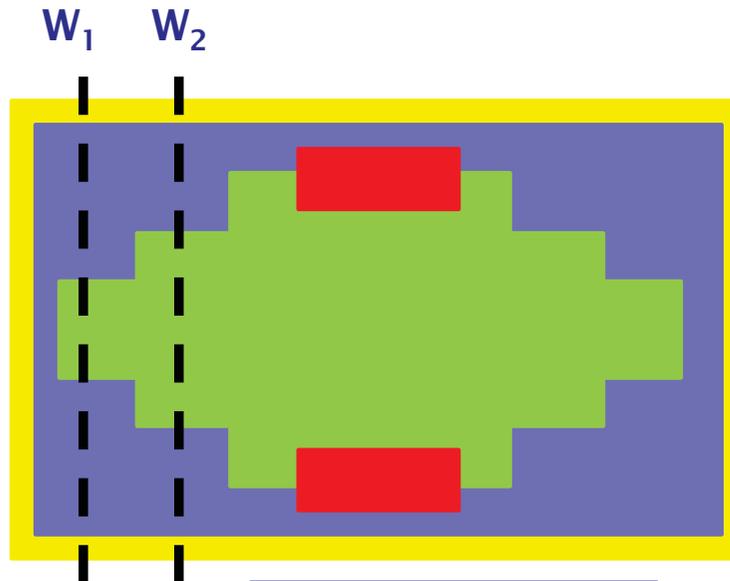
Capacity density
sets the limit to in-
pixel storage

Charges in the diode

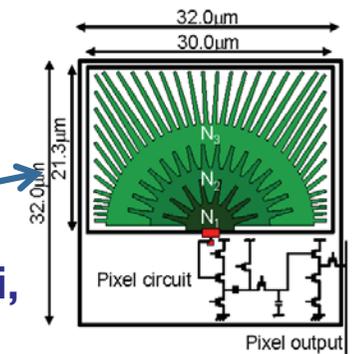
'W effect'



Lahav 2013



Miyauchi, 2014



Charge storage

CCD-in-CMOS

Tower 180 nm

CIS

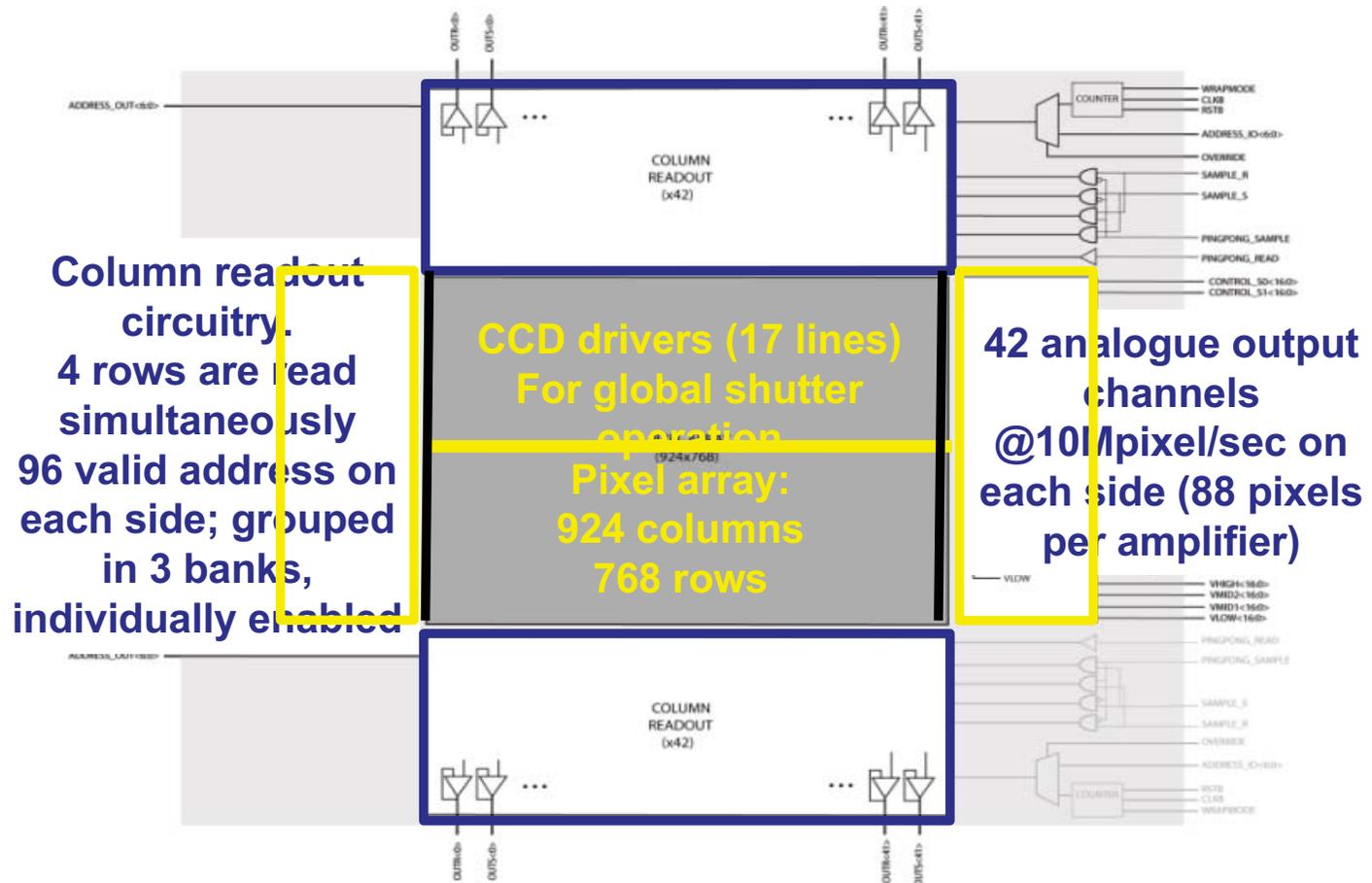
CCD module

developed for

the frame

storage, in the

pixel

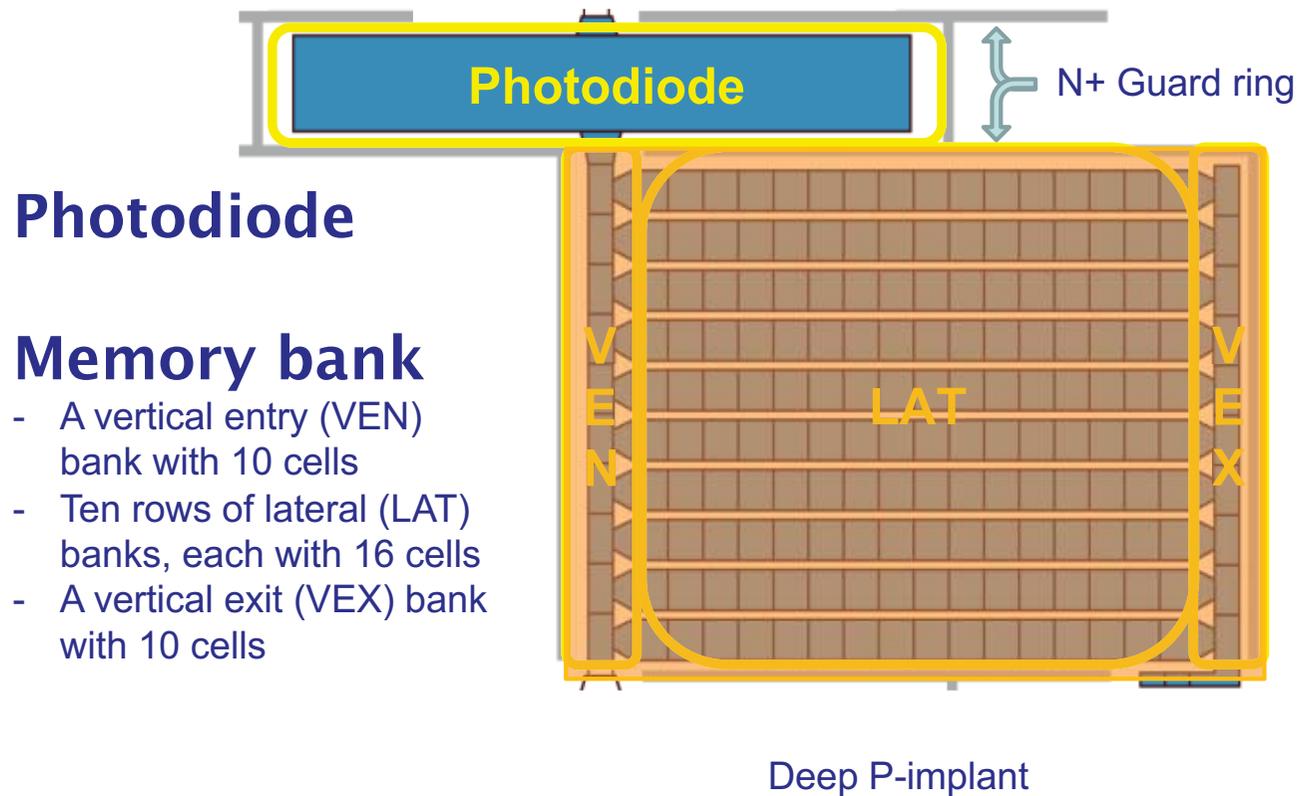


Column readout circuitry. 4 rows are read simultaneously 96 valid address on each side; grouped in 3 banks, individually enabled

CCD drivers (17 lines) For global shutter operation
Pixel array: 924 columns 768 rows

42 analogue output channels @10Mpixel/sec on each side (88 pixels per amplifier)

Kirana pixel

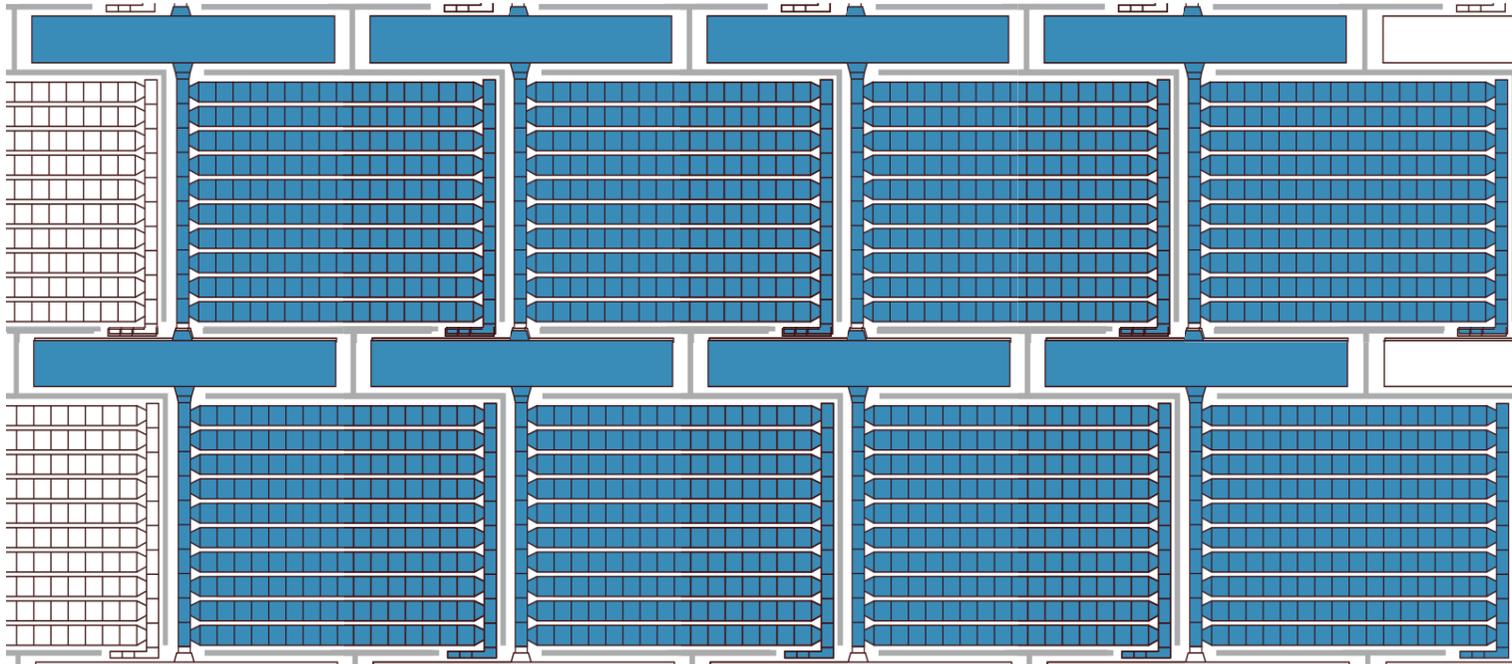


Photodiode

Memory bank

- A vertical entry (VEN) bank with 10 cells
- Ten rows of lateral (LAT) banks, each with 16 cells
- A vertical exit (VEX) bank with 10 cells

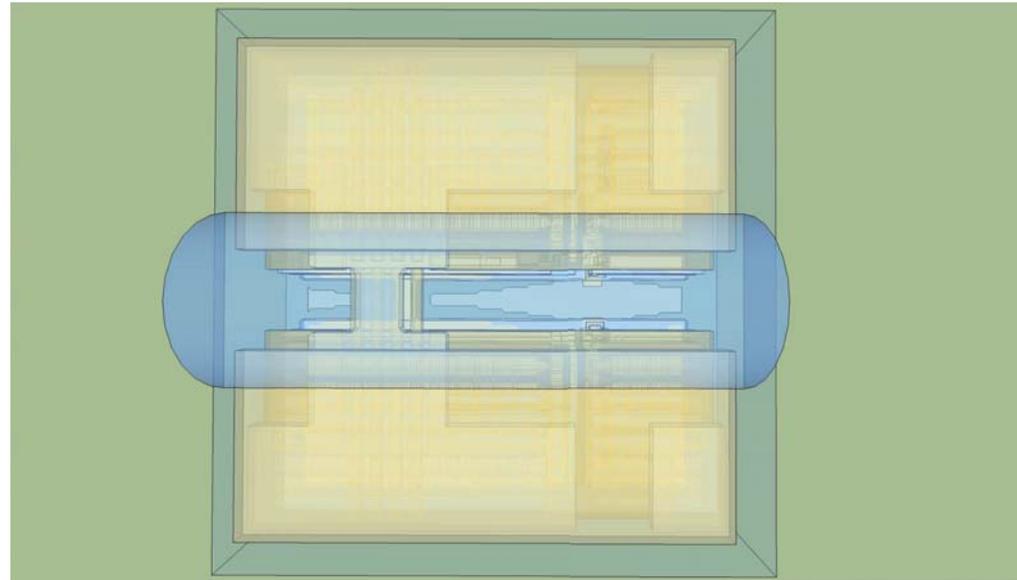
Kirana array



Highly scalable architecture:

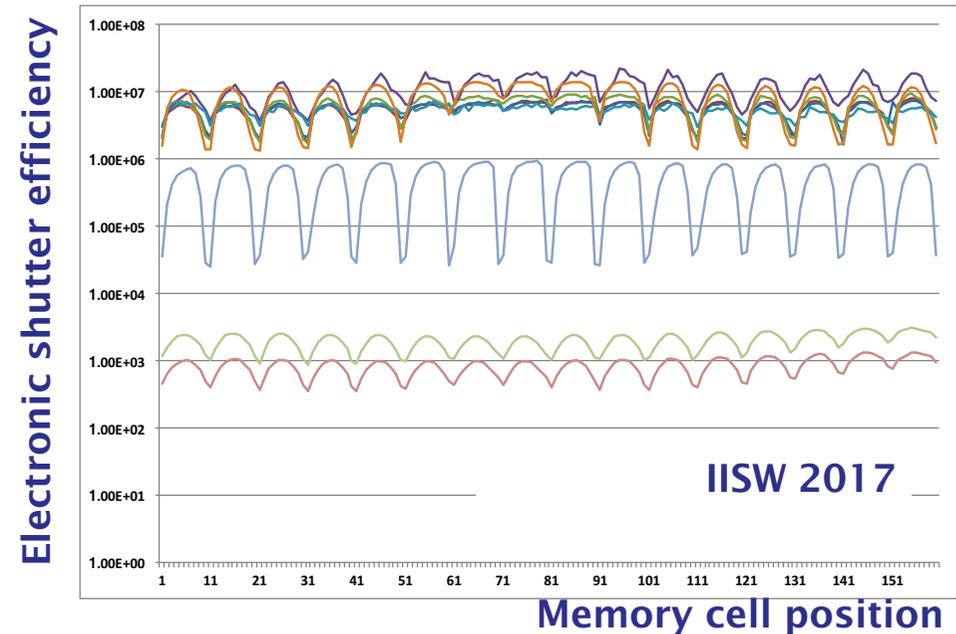
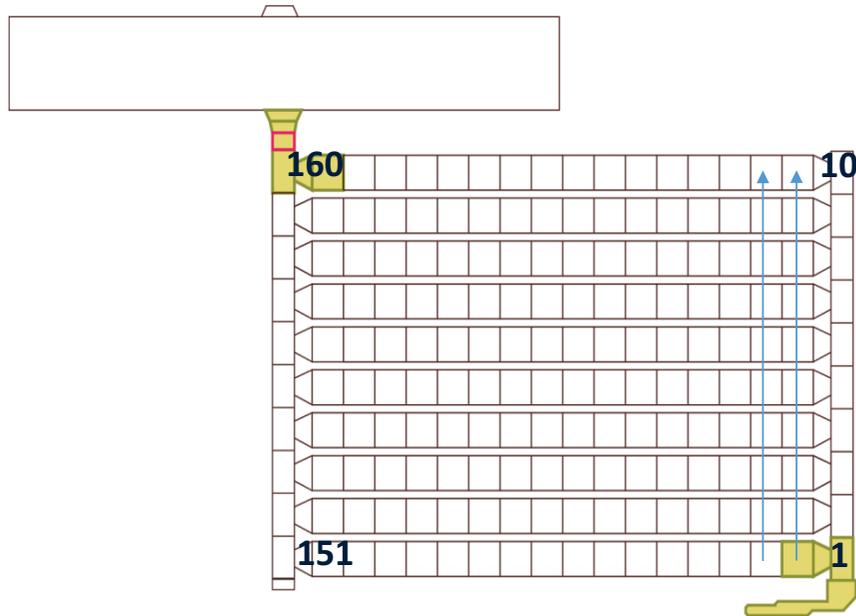
- Number of memory cells
- Number of pixels
- In-pixel storage: minimal load
- Low power

Kirana improvements



- A) Microlenses for improved sensitivity: 2.5 improvement
- B) High-resistivity wafers for faster collection time
- C) Optical shielding of the memory cells
- D) Improved implants for electrical shielding of the memory cell

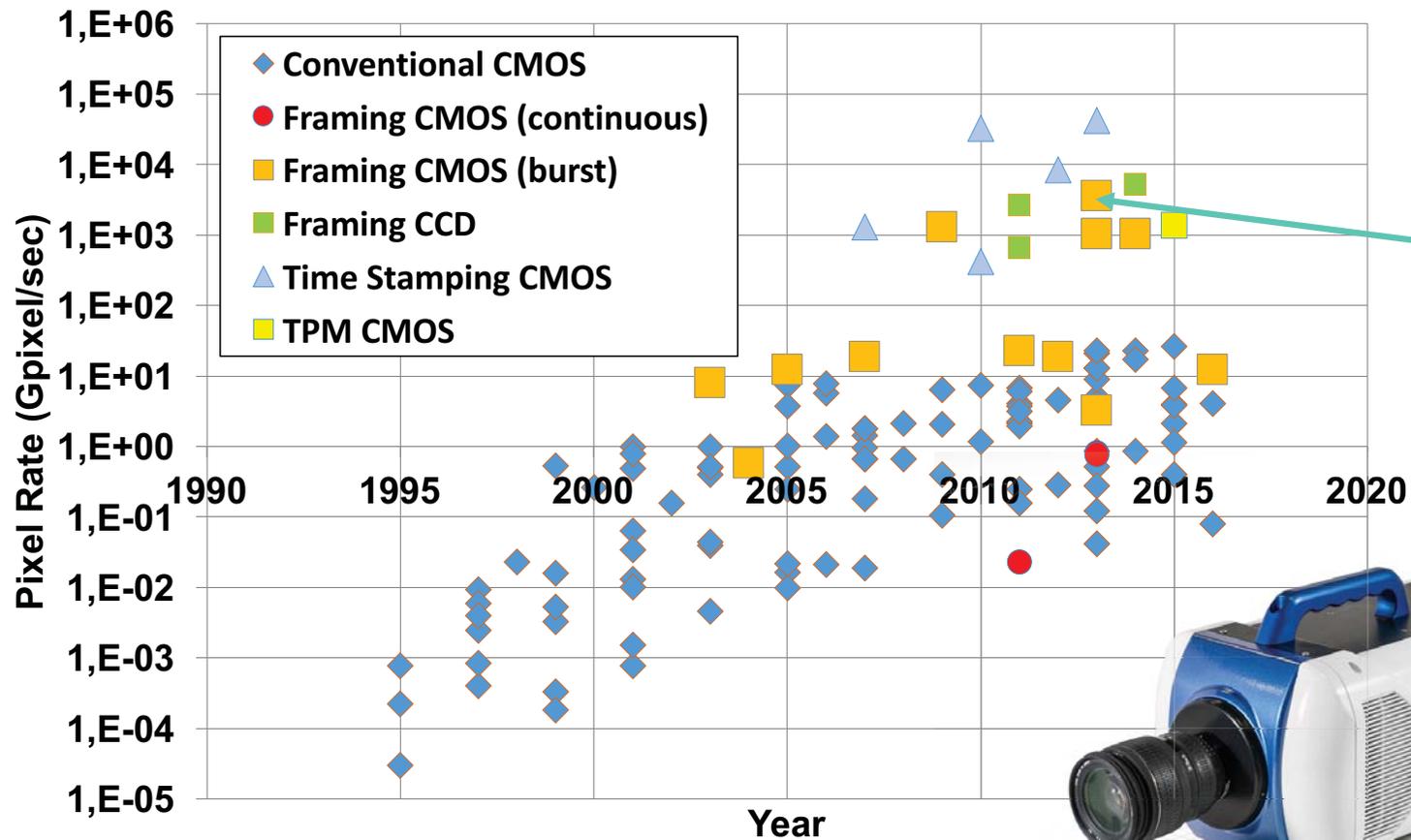
Electronic shutter efficiency



Electronic shutter efficiency $> 10^7$

In excess of 1,000 improvement with respect to the first sensors (presented at IISW 2013)

Ultra high-speed summary



Kirana



Conclusions

- **Continuous frame rate. State of the art > 10Gpixel/sec**
- > 100Gpixel/sec, i.e. 100kfps @ 1Mpixel
- **Sensors for Gfps: time stamping, time pixel multiplexing, burst mode sensors**
- **Burst mode technologies : charge and voltage sampling**
- **Burst mode. State of the art > Tpixel/sec, i.e. >Mfps @ 1Mpixel**
- **Ultimate limit from charge movement → 10-100 Gfps**
- **High density capacitance and 3D stacking can help**

Thank you!

imasenic